TOSHIBA Field Effect Transistor Silicon N Channel MOS Type (U-MOS II)

# **TPCS8205**

Lithium Ion Battery Applications
Portable Equipment Applications
Notebook PCs

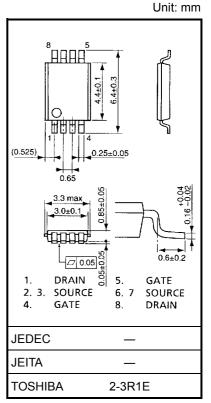
- Small footprint due to small and thin package
- Low drain-source ON resistance:  $RDS(ON) = 30 \text{ m}\Omega$  (typ.)
- High forward transfer admittance:  $|Y_{fs}| = 10 \text{ S (typ.)}$
- Low leakage current:  $I_{DSS} = 10 \mu A \text{ (max) (V}_{DS} = 20 \text{ V)}$
- Enhancement-mode:  $V_{th} = 0.5 \sim 1.2 \text{ V (VDS} = 10 \text{ V, ID} = 200 \text{ }\mu\text{A})$

### **Maximum Ratings (Ta = 25°C)**

Char	acteristics	Symbol	Rating	Unit	
Drain-source vol	tage	$V_{DSS}$	20	V	
Drain-gate voltag	ge (R <sub>GS</sub> = 20kΩ)	$V_{DGR}$	20	V	
Gate-source volt	age	V <sub>GSS</sub>	±12	V	
Drain curren	D C (Note 1)	I <sub>D</sub>	5	Α	
Diain curren	Pulse (Note 1)	I <sub>DP</sub>	20 20 ±12	_ A	
Drain power dissipation (t = 10s) (Note 2a)	Single-device operation (Note 3a)	P <sub>D (1)</sub>	1.1	W	
	Single-device value at dual operation (Note 3b)	P <sub>D(2)</sub>	0.5		
Drain power dissipation (t = 10s) (Note 2b)	Single-device operation (Note 3a)	P <sub>D (1)</sub>	0.6	W	
	Single-device value at dual operation (Note 3b)	P <sub>D (2)</sub>	0.35		
Single pulse ava	lanche energy (Note 4)	E <sub>AS</sub>	32.5	mJ	
Avalanche curre	nt	$I_{AR}$	5	Α	
Repetitive avalar Single-device va (Note		E <sub>AR</sub>	0.05	mJ	
Channel tempera	ature	T <sub>ch</sub>	150	°C	
Storage tempera	ture range	T <sub>stg</sub>	-55~150	°C	

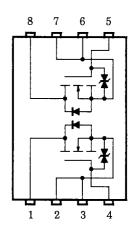
Note: For (Note 1), (Note 2a), (Note 2b), (Note 3a), (Note 3b), (Note 4) and (Note 5), please refer to the next page.

This transistor is an electrostatic sensitive device. Please handle with caution.



Weight: 0.035 g (typ.)

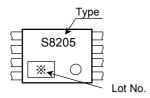
### **Circuit Configuration**



#### **Thermal Characteristics**

Characteristics	Symbol	Max	Unit		
Thermal resistance, channel to ambient (t = 10s) (Note 2a)	Single-device operation (Note 3a)	R <sub>th (ch-a) (1)</sub>	114		
	Single-device value at dual operation (Note 3b)	R <sub>th (ch-a) (2)</sub>	250	°C/W	
Thermal resistance, channel to ambient	Single-device operation (Note 3a)	R <sub>th (ch-a) (1)</sub>	208	C/VV	
(t = 10s) (Note 2b)	Single-device value at dual operation (Note 3b)	R <sub>th (ch-a) (2)</sub>	357		

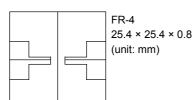
### Marking (Note 6)



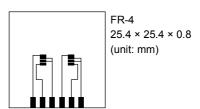
Note 1: Please use devices on condition that the channel temperature is below 150°C.

Note 2:

a) Device mounted on a glass-epoxy board (a)



Device mounted on a glass-epoxy board (b)



Note 3:

- a) The power dissipation and thermal resistance values are shown for a single device (During single-device operation, power is only applied to one device.)
- b) The power dissipation and thermal resistance values are shown for a single device (During dual operation, power is evenly applied to both devices.)

Note 4:  $V_{DD}$  = 16 V,  $T_{ch}$  = 25°C (Initiaal), L = 1.0 mH,  $R_G$  = 25  $\Omega$ ,  $I_{AR}$  = 5.0 A

Note 5: Repetitive rating: pulse width limited by max channel temperature

Note 6: O on lower right of the marking indicates Pin 1.

Weekly code: (Three digits)
 Week of manufacture
 (01 for first week of year, continues up to 52 or 53)
 Year of manufacture
 (One low-order digits of calendar year)

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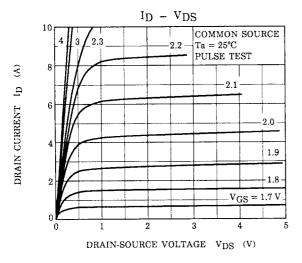
# Electrical Characteristics (Ta = 25°C)

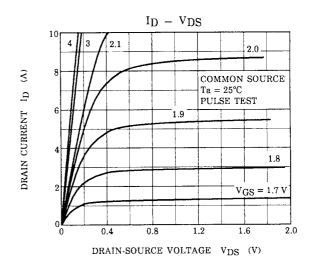
Characteristics		Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage current		I <sub>GSS</sub>	V <sub>GS</sub> = ±10 V, V <sub>DS</sub> = 0 V	_	_	±10	μA
Drain cut-OFF cui	rrent	I <sub>DSS</sub>	V <sub>DS</sub> = 20 V, V <sub>GS</sub> = 0 V		_	10	μA
Drain-source brea	akdown voltage	V (BR) DSS	I <sub>D</sub> = 10 mA, V <sub>GS</sub> = 0 V 20	_	_	٧	
Drain-source breakdown voltage		V (BR) DSX	I <sub>D</sub> = 10 mA, V <sub>GS</sub> = -12 V	8	_		_
Gate threshold vo	ltage	V <sub>th</sub>	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 200 μA	0.5	_	1.2	V
		R <sub>DS</sub> (ON)	V <sub>GS</sub> = 2.0 V, I <sub>D</sub> = 3.5 A	_	60	90	mΩ
Drain-source ON	resistance	R <sub>DS</sub> (ON)	V <sub>GS</sub> = 2.5 V, I <sub>D</sub> = 3.5 A	_	40	60	
		R <sub>DS</sub> (ON)	V <sub>GS</sub> = 4 V, I <sub>D</sub> = 4 A	_	30	45	
Forward transfer admittance		Y <sub>fs</sub>	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 2.5 A	5	10	_	S
Input capacitance		C <sub>iss</sub>	V <sub>DS</sub> = 10 V, V <sub>GS</sub> = 0 V, f = 1 MHz	_	760	_	pF
Reverse transfer	capacitance	C <sub>rss</sub>		_	110	_	pF
Output capacitance		C <sub>oss</sub>		_	130	_	pF
Switching time	Rise time	t <sub>r</sub>	$V_{GS} \stackrel{5 \text{ V}}{\underset{0 \text{ V}}{\text{V}}} \stackrel{I_{D} = 2.5 \text{ A}}{\underset{V_{OUT}}{\text{V}}} \stackrel{V_{OUT}}{\underset{R_{L} = 4 \Omega}{\text{V}}} \stackrel{R_{L} = 4 \Omega}{\underset{V_{DD}}{\text{V}}} = 10 \text{ V}$	_	7		
	Turn-ON time	t <sub>on</sub>			13		ns
	Fall time	t <sub>f</sub>		_	13	_	
	Turn-OFF time	t <sub>off</sub>		_	49	_	
Total gate charge (gate-source plus gate-drain)		Qg	V <sub>DD</sub> ≈ 16 V, V <sub>GS</sub> = 5 V, I <sub>D</sub> = 5 A	_	11	_	nC
Gate-source charge		Q <sub>gs</sub>			8		nC
Gate-drain ("miller") charge		Q <sub>gd</sub>			3		nC

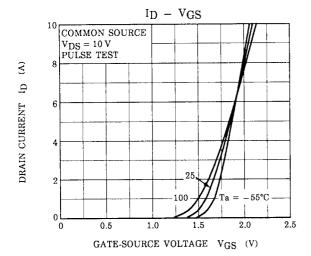
## **Source-Drain Ratings and Characteristics (Ta = 25°C)**

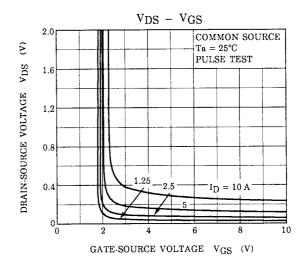
Charact	eristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Drain reverse current	Pulse (Note 1)	I <sub>DRP</sub>		_		20	Α
Forward voltage (	(diode)	$V_{DSF}$	$I_{DR} = 5 A$ , $V_{GS} = 0 V$	-		-1.2	V

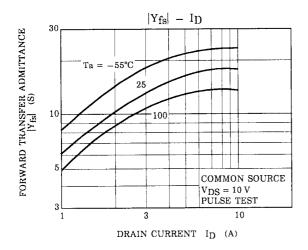
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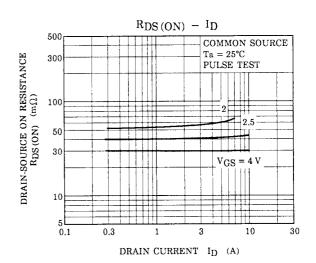


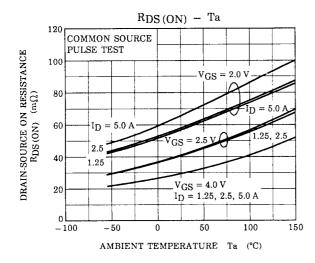


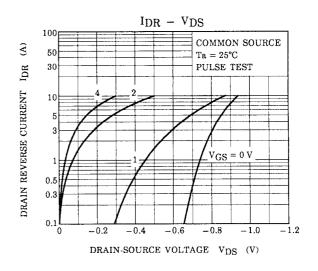


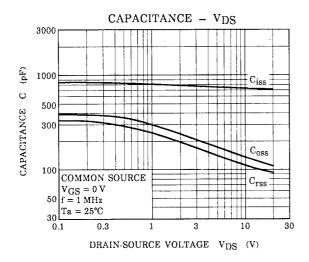


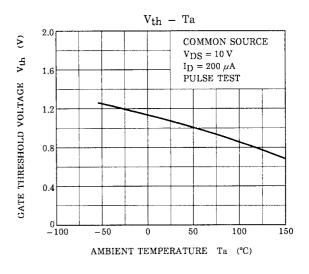


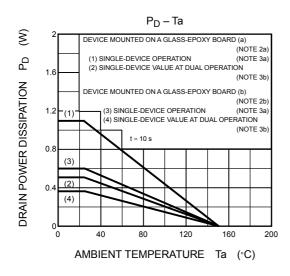


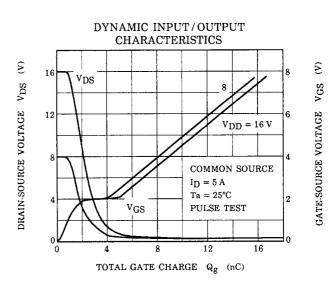




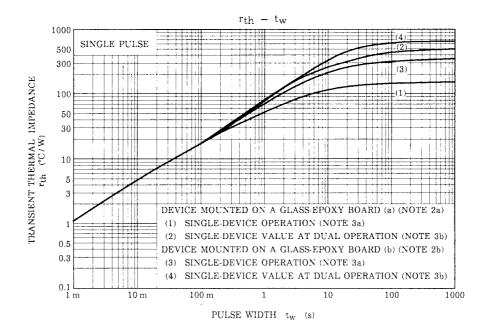




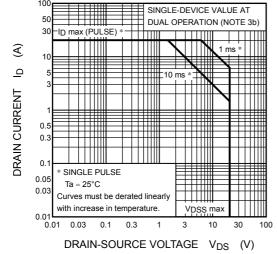


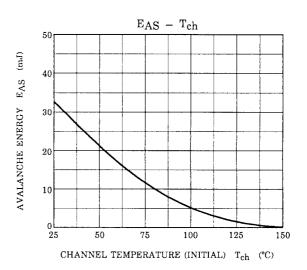


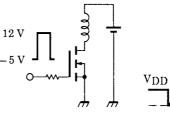
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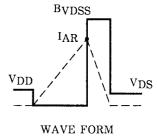








TEST CIRCUIT



 $\begin{array}{l} T_{ch}=25^{\circ}C \ (Initial) \\ Peak \ I_{AR}=5 \ A, \ R_{G}=25 \ \Omega \\ V_{DD}=16 \ V, \ L=1.0 \ mH \end{array} \\ \to AS=\frac{1}{2} \cdot L \cdot I^{2} \cdot ( \ \frac{BVDSS}{BVDSS-V_{DD}} )$ 

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